

Notice of References Cited		Application/Control No.	Applicant(s)/Patent Under Reexamination CHEN ET AL.	
		Examiner Evral Bodden	Art Unit 2109	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,493,682	02-1996	Tyra et al.	717/122
*	B	US-4,989,132	01-1991	Mellender et al.	717/139
*	C	US-6,249,905	06-2001	Yoshida et al.	717/100
*	D	US-52,109 A1	01-1866	Nagashima et al.	416/72
*	E	US-6,557,165 B1	04-2003	Nagashima et al.	717/108
*	F	US-5,864,862	01-1999	Kriens et al.	707/103R
*	G	US-5,437,027	07-1995	Bannon et al.	707/103R
*	H	US-5,297,279	03-1994	Bannon et al.	707/103R
*	I	US-6,377,951	04-2002	Campbell, R. David L.	707/10
*	J	US-5,758,160	05-1998	McInerney et al.	717/104
*	K	US-2004/0015831	01-2004	Bowhill, Allan J.C.	717/106
*	L	US-5,694,596	12-1997	Campbell, R. David L.	707/10
*	M	US-5,937,405	08-1999	Campbell, R. David L.	707/10

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	WO 2001/31439	05-2001	USA	Method and Apparatus for	
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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